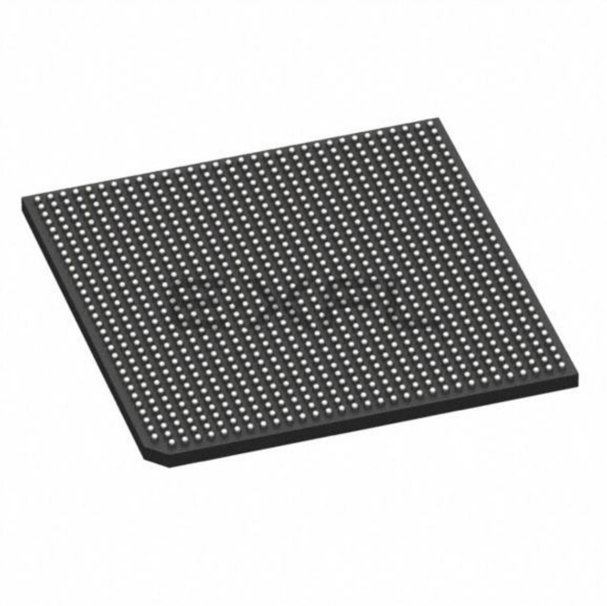
NXP USA Inc. - MC8641DVU1250HC Datasheet



Welcome to E-XFL.COM

Understanding Embedded - Microprocessors

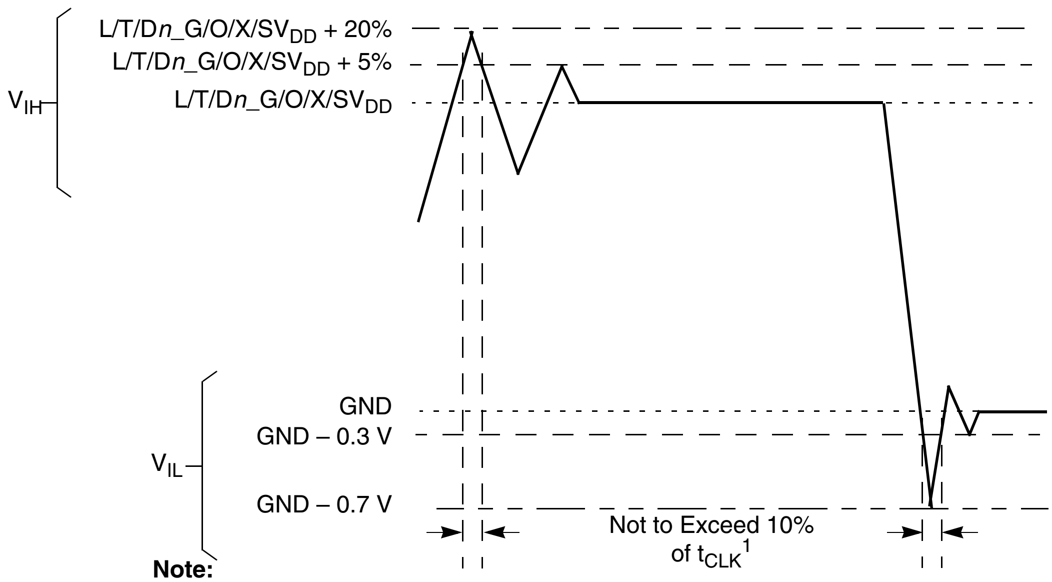
Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e600
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.25GHz
Co-Processors/DSP	-
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	1023-BCBGA, FCCBGA
Supplier Device Package	1023-FCCBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc8641dvu1250hc

Figure 2 shows the undershoot and overshoot voltages at the interfaces of the MPC8641.



Note:
1. t_{CLK} references clocks for various functional blocks as follows:

DDR*n* = 10% of D*n*_MCK period
eTSEC*n* = 10% of EC*n*_GTX_CLK125 period
Local Bus = 10% of LCLK[0:2] period
I^2C = 10% of SYSCLK
JTAG = 10% of SYSCLK

Figure 2. Overshoot/Undershoot Voltage for D*n*_M/O/L/TV$_{IN}$

The MPC8641 core voltage must always be provided at nominal V_{DD}_Core*n* (See Table 2 for actual recommended core voltage). Voltage to the processor interface I/Os are provided through separate sets of supply pins and must be provided at the voltages shown in Table 2. The input voltage threshold scales with respect to the associated I/O supply voltage. OV_{DD} and L/TV_{DD} based receivers are simple CMOS I/O circuits and satisfy appropriate LVCMOS type specifications. The DDR SDRAM interface uses a single-ended differential receiver referenced to each externally supplied D*n*_MV_{REF} signal (nominally set to D*n*_GV_{DD}/2) as is appropriate for the (SSTL-18 and SSTL-25) electrical signaling standards.

The maximum power dissipation for individual power supplies of the MPC8641D is shown in Table 5.

Table 5. MPC8641D Individual Supply Maximum Power Dissipation [1]

Component Description	Supply Voltage (Volts)	Power (Watts)	Notes
Per Core voltage Supply	V_{DD}_Core0/V_{DD}_Core1 = 1.1 V @ 1500 MHz	21.00	
Per Core PLL voltage supply	AV_{DD}_Core0/AV_{DD}_Core1 = 1.1 V @ 1500 MHz	0.0125	
Per Core voltage Supply	V_{DD}_Core0/V_{DD}_Core1 = 1.05 V @ 1333 MHz	17.00	
Per Core PLL voltage supply	AV_{DD}_Core0/AV_{DD}_Core1 = 1.05 V @ 1333 MHz	0.0125	
Per Core voltage Supply	V_{DD}_Core0/V_{DD}_Core1 = 0.95 V @ 1000 MHz	11.50	5
Per Core PLL voltage supply	AV_{DD}_Core0/AV_{DD}_Core1 = 0.95 V @ 1000 MHz	0.0125	5
DDR Controller I/O voltage supply	D*n*_GV_{DD} = 2.5 V @ 400 MHz	0.80	2
	D*n*_GV_{DD} = 1.8 V @ 533 MHz	0.68	2
	D*n*_GV_{DD} = 1.8 V @ 600 MHz	0.77	2
16-bit FIFO @ 200 MHz eTsec 1&2/3&4 Voltage Supply	L/TV_{DD} = 3.3 V	0.11	2, 3
non-FIFO eTsec*n* Voltage Supply	L/TV_{DD} = 3.3 V	0.08	2
x8 SerDes transceiver Supply	SV_{DD} = 1.1 V	0.70	2
x8 SerDes I/O Supply	XV_{DD}_SRDS*n* = 1.1 V	0.66	2
SerDes PLL voltage supply Port 1 or 2	AV_{DD}_SRDS1/AV_{DD}_SRDS2 = 1.1 V	0.10	
Platform I/O Supply	OV_{DD} = 3.3 V	0.45	4
Platform source Supply	V_{DD}_PLAT = 1.1 V @ 600 MHz	12.00	
Platform source Supply	V_{DD}_PLAT = 1.05 Vn @ 500 MHz	9.80	5
Platform source Supply	V_{DD}_PLAT = 1.05 Vn @ 400 MHz	7.70	
Platform, Local Bus PLL voltage Supply	AV_{DD}_PLAT, AV_{DD}_LB = 1.1 V	0.0125	

Notes:
1. This is a maximum power supply number which is provided for power supply and board design information. The numbers are based on 100% bus utilization for each component. The components listed are not expected to have 100% bus usage simultaneously for all components. Actual numbers may vary based on activity.
2. Number is based on a per port/interface value.
3. This is based on one eTSEC port used. Since 16-bit FIFO mode involves two ports, the number will need to be multiplied by two for the total. The other eTSEC protocols dissipate less than this number per port. Note that the power needs to be multiplied by the number of ports used for the protocol for the total eTSEC port power dissipation.
4. This includes Local Bus, DUART, I^2C, DMA, Multiprocessor Interrupts, System Control & Clocking, Debug, Test, Power management, JTAG and Miscellaneous I/O voltage.
5. These power numbers are for Part Number MC8641xxx1000NX only. V_{DD}_Core*n* = 0.95 V and V_{DD}_PLAT = 1.05 V.

Table 10. ECn_GTX_CLK125 AC Timing Specifications (continued)

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
EC*n*_GTX_CLK125 duty cycle GMII, TBI 1000Base-T for RGMII, RTBI	t_{G125H}/t_{G125}	 45 47	—	 55 53	%	1, 2

Notes:
1. Timing is guaranteed by design and characterization.
2. EC*n*_GTX_CLK125 is used to generate the GTX clock for the eTSEC transmitter with 2% degradation. EC*n*_GTX_CLK125 duty cycle can be loosened from 47/53% as long as the PHY device can tolerate the duty cycle generated by the eTSEC GTX_CLK. See Section 8.2.6, "RGMII and RTBI AC Timing Specifications," for duty cycle for 10Base-T and 100Base-T reference clock.
3. ±100 ppm tolerance on EC*n*_GTX_CLK125 frequency

NOTE

The phase between the output clocks TSEC1_GTX_CLK and TSEC2_GTX_CLK (ports 1 and 2) is no more than 100 ps. The phase between the output clocks TSEC3_GTX_CLK and TSEC4_GTX_CLK (ports 3 and 4) is no more than 100 ps.

4.4 Platform Frequency Requirements for PCI-Express and Serial RapidIO

The MPX platform clock frequency must be considered for proper operation of the high-speed PCI Express and Serial RapidIO interfaces as described below.

For proper PCI Express operation, the MPX clock frequency must be greater than or equal to:

$$\frac{527\text{ MHz} \times (\text{PCI-Express link width})}{16 / (1 + \text{cfg\_plat\_freq})}$$

Note that at MPX = 400 MHz, cfg_plat_freq = 0 and at MPX > 400 MHz, cfg_plat_freq = 1. Therefore, when operating PCI Express in x8 link width, the MPX platform frequency must be 400 MHz with cfg_plat_freq = 0 or greater than or equal to 527 MHz with cfg_plat_freq = 1.

For proper Serial RapidIO operation, the MPX clock frequency must be greater than or equal to:

$$\frac{2 \times (0.8512) \times (\text{Serial RapidIO interface frequency}) \times (\text{Serial RapidIO link width})}{64}$$

4.5 Other Input Clocks

For information on the input clocks of other functional blocks of the platform such as SerDes, and eTSEC, see the specific section of this document.

6 DDR and DDR2 SDRAM

This section describes the DC and AC electrical specifications for the DDR SDRAM interface of the MPC8641. Note that DDR SDRAM is Dn_GV_{DD}(typ) = 2.5 V and DDR2 SDRAM is Dn_GV_{DD}(typ) = 1.8 V.

6.1 DDR SDRAM DC Electrical Characteristics

Table 13 provides the recommended operating conditions for the DDR2 SDRAM component(s) of the MPC8641 when Dn_GV_{DD}(typ) = 1.8 V.

Table 13. DDR2 SDRAM DC Electrical Characteristics for Dn_GV_{DD}(typ) = 1.8 V

Parameter/Condition	Symbol	Min	Max	Unit	Notes
I/O supply voltage	Dn_GV_{DD}	1.71	1.89	V	1
I/O reference voltage	Dn_MV_{REF}	0.49 × Dn_GV_{DD}	0.51 × Dn_GV_{DD}	V	2
I/O termination voltage	V_{TT}	Dn_MV_{REF} – 0.04	Dn_MV_{REF} + 0.04	V	3
Input high voltage	V_{IH}	Dn_MV_{REF}+ 0.125	Dn_GV_{DD} + 0.3	V	—
Input low voltage	V_{IL}	–0.3	Dn_MV_{REF} – 0.125	V	—
Output leakage current	I_{OZ}	–50	50	μA	4
Output high current (V_{OUT} = 1.420 V)	I_{OH}	–13.4	—	mA	—
Output low current (V_{OUT} = 0.280 V)	I_{OL}	13.4	—	mA	—

Notes:
1. Dn_GV_{DD} is expected to be within 50 mV of the DRAM Dn_GV_{DD} at all times.
2. Dn_MV_{REF} is expected to be equal to 0.5 × Dn_GV_{DD}, and to track Dn_GV_{DD} DC variations as measured at the receiver. Peak-to-peak noise on Dn_MV_{REF} may not exceed ±2% of the DC value.
3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to be equal to Dn_MV_{REF}. This rail should track variations in the DC level of Dn_MV_{REF}.
4. Output leakage is measured with all outputs disabled, 0 V ≤ V_{OUT} ≤ Dn_GV_{DD}.

Table 14 provides the DDR2 capacitance when Dn_GV_{DD}(typ) = 1.8 V.

Table 14. DDR2 SDRAM Capacitance for Dn_GV_{DD}(typ)=1.8 V

Parameter/Condition	Symbol	Min	Max	Unit	Notes
Input/output capacitance: DQ, DQS, $\overline{DQS}$	C_{IO}	6	8	pF	1
Delta input/output capacitance: DQ, DQS, $\overline{DQS}$	C_{DIO}	—	0.5	pF	1

Note:
1. This parameter is sampled. Dn_GV_{DD} = 1.8 V ± 0.090 V, f = 1 MHz, T_A = 25°C, V_{OUT} = Dn_GV_{DD}/2, V_{OUT} (peak-to-peak) = 0.2 V.

6.2 DDR SDRAM AC Electrical Characteristics

This section provides the AC electrical characteristics for the DDR SDRAM interface.

6.2.1 DDR SDRAM Input AC Timing Specifications

Table 18 provides the input AC timing specifications for the DDR2 SDRAM when Dn_GV_{DD}(typ)=1.8 V.

Table 18. DDR2 SDRAM Input AC Timing Specifications for 1.8-V Interface

At recommended operating conditions

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage 400, 533 MHz 600 MHz	V_{IL}	—	 Dn_MV_{REF} – 0.25 Dn_MV_{REF} – 0.20	V	—
AC input high voltage 400, 533 MHz 600 MHz	V_{IH}	 Dn_MV_{REF} + 0.25 Dn_MV_{REF} + 0.20	—	V	—

Table 19 provides the input AC timing specifications for the DDR SDRAM when Dn_GV_{DD}(typ)=2.5 V.

Table 19. DDR SDRAM Input AC Timing Specifications for 2.5-V Interface

At recommended operating conditions.

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage	V_{IL}	—	Dn_MV_{REF} – 0.31	V	—
AC input high voltage	V_{IH}	Dn_MV_{REF} + 0.31	—	V	—

Table 20 provides the input AC timing specifications for the DDR SDRAM interface.

Table 20. DDR SDRAM Input AC Timing Specifications

At recommended operating conditions.

Parameter	Symbol	Min	Max	Unit	Notes
Controller Skew for MDQS—MDQ/MECC	t_{CISKEW}	—		ps	1, 2
600 MHz	—	–240	240	—	3
533 MHz	—	–300	300	—	3
400 MHz	—	–365	365	—	—

Note:

1. t_{CISKEW} represents the total amount of skew consumed by the controller between MDQS[n] and any corresponding bit that will be captured with MDQS[n]. This should be subtracted from the total timing budget.
2. The amount of skew that can be tolerated from MDQS to a corresponding MDQ signal is called t_{DISKEW}. This can be determined by the following equation: t_{DISKEW} =+/–(T/4 – abs(t_{CISKEW})) where T is the clock period and abs(t_{CISKEW}) is the absolute value of t_{CISKEW}.
3. Maximum DDR1 frequency is 400 MHz.

8.2.3 MII AC Timing Specifications

This section describes the MII transmit and receive AC timing specifications.

8.2.3.1 MII Transmit AC Timing Specifications

Table 30 provides the MII transmit AC timing specifications.

Table 30. MII Transmit AC Timing Specifications

At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
TX_CLK clock period 10 Mbps	t_{MTX} [2]	—	400	—	ns
TX_CLK clock period 100 Mbps	t_{MTX}	—	40	—	ns
TX_CLK duty cycle	t_{MTXH}/t_{MTX}	35	—	65	%
TX_CLK to MII data TXD[3:0], TX_ER, TX_EN delay	t_{MTKHDX}	1	5	15	ns
TX_CLK data clock rise time (20%-80%)	t_{MTXR} [2]	1.0	—	4.0	ns
TX_CLK data clock fall time (80%-20%)	t_{MTXF} [2]	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Guaranteed by design.

Figure 13 shows the MII transmit AC timing diagram.

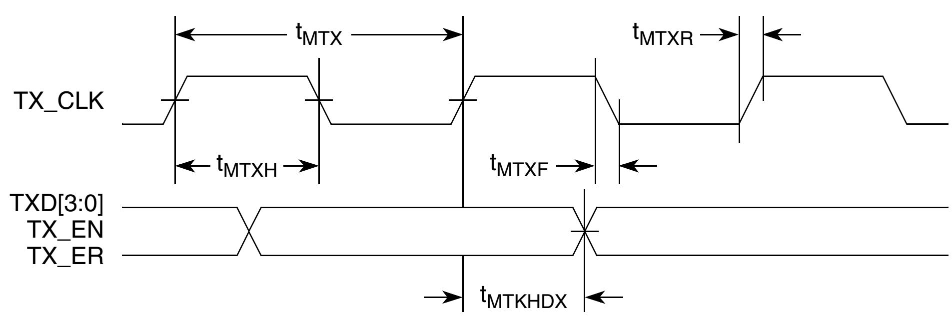


Figure 13. MII Transmit AC Timing Diagram

8.2.3.2 MII Receive AC Timing Specifications

Table 31 provides the MII receive AC timing specifications.

Table 31. MII Receive AC Timing Specifications

At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}[2,3]	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}[3]	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise time (20%-80%)	t_{MRXR}[2]	1.0	—	4.0	ns
RX_CLK clock fall time (80%-20%)	t_{MRXF}[2]	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Guaranteed by design.
3. ±100 ppm tolerance on RX_CLK frequency

Figure 14 provides the AC test load for eTSEC.

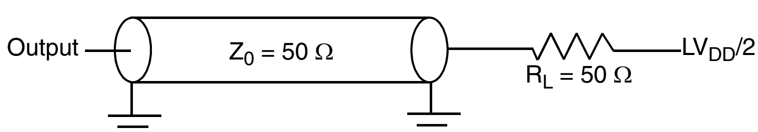


Figure 14. eTSEC AC Test Load

Figure 15 shows the MII receive AC timing diagram.

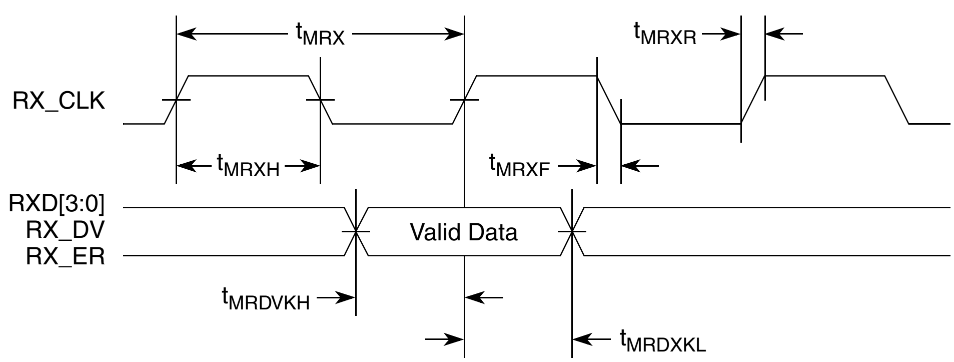


Figure 15. MII Receive AC Timing Diagram

Table 35. RGMII and RTBI AC Timing Specifications (continued)

At recommended operating conditions with L/TV_{DD} of 2.5 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
Clock period duration [3]	t_{RGT}[5,6]	7.2	8.0	8.8	ns
Duty cycle for 10BASE-T and 100BASE-TX [3, 4]	t_{RGTH}/t_{RGT}[5]	40	50	60	%
Rise time (20%–80%)	t_{RGTR}[5]	—	—	0.75	ns
Fall time (80%–20%)	t_{RGTF}[5]	—	—	0.75	ns

Notes:

1. Note that, in general, the clock reference symbol representation for this section is based on the symbols RGT to represent RGMII and RTBI timing. For example, the subscript of t_{RGT} represents the TBI (T) receive (RX) clock. Note also that the notation for rise (R) and fall (F) times follows the clock symbol that is being represented. For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (RGT).
2. This implies that PC board design will require clocks to be routed such that an additional trace delay of greater than 1.5 ns will be added to the associated clock signal.
3. For 10 and 100 Mbps, t_{RGT} scales to 400 ns ± 40 ns and 40 ns ± 4 ns, respectively.
4. Duty cycle may be stretched/shrunk during speed changes or while transitioning to a received packet's clock domains as long as the minimum duty cycle is not violated and stretching occurs for no more than three t_{RGT} of the lowest speed transitioned between.
5. Guaranteed by characterization
6. ±100 ppm tolerance on RX_CLK frequency

Figure 19 shows the RGMII and RTBI AC timing and multiplexing diagrams.

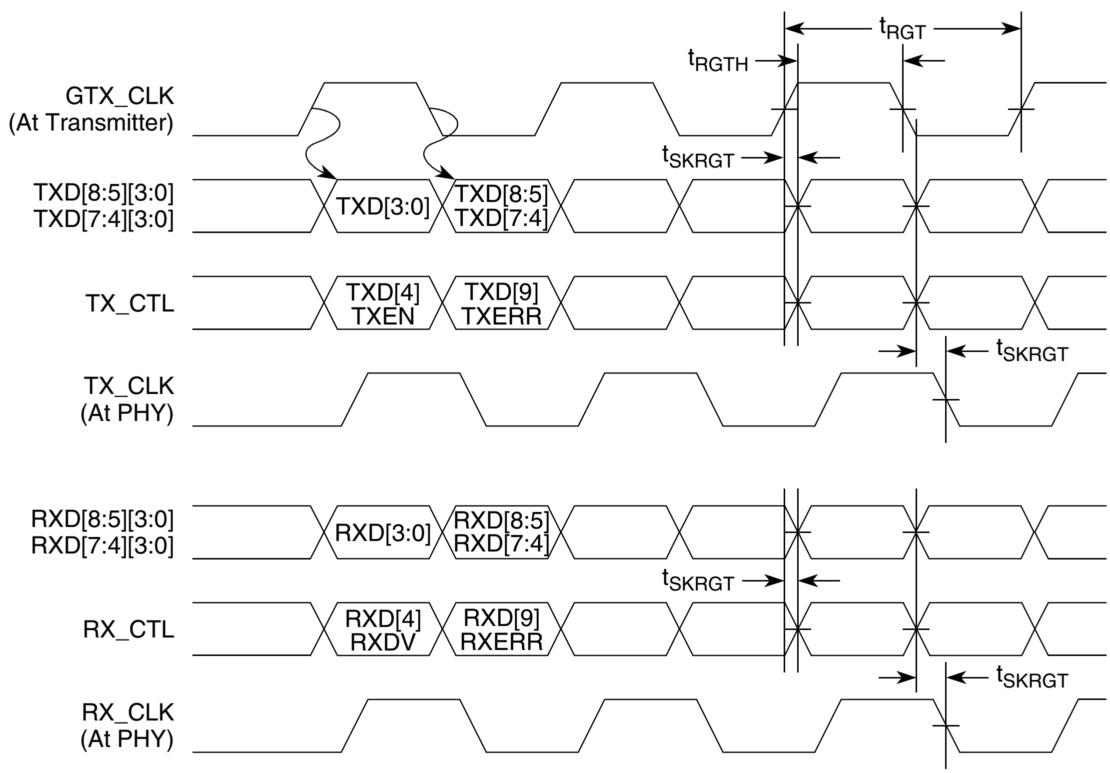


Figure 19. RGMII and RTBI AC Timing and Multiplexing Diagrams

8.2.7.2 RMII Receive AC Timing Specifications

Table 37. RMII Receive AC Timing Specifications

At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
REF_CLK clock period	t_{RMR}	15.0	20.0	25.0	ns
REF_CLK duty cycle	t_{RMRH}/t_{RMR}	35	50	65	%
REF_CLK peak-to-peak jitter	t_{RMRJ}	—	—	250	ps
Rise time REF_CLK (20%–80%)	t_{RMRR}	1.0	—	2.0	ns
Fall time REF_CLK (80%–20%)	t_{RMRF}	1.0	—	2.0	ns
RXD[1:0], CRS_DV, RX_ER setup time to REF_CLK rising edge	t_{RMRDV}	4.0	—	—	ns
RXD[1:0], CRS_DV, RX_ER hold time to REF_CLK rising edge	t_{RMRDX}	2.0	—	—	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 21 provides the AC test load for eTSEC.

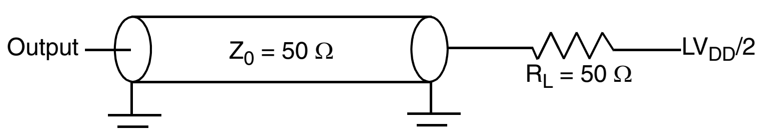


Figure 21. eTSEC AC Test Load

Figure 22 shows the RMII receive AC timing diagram.

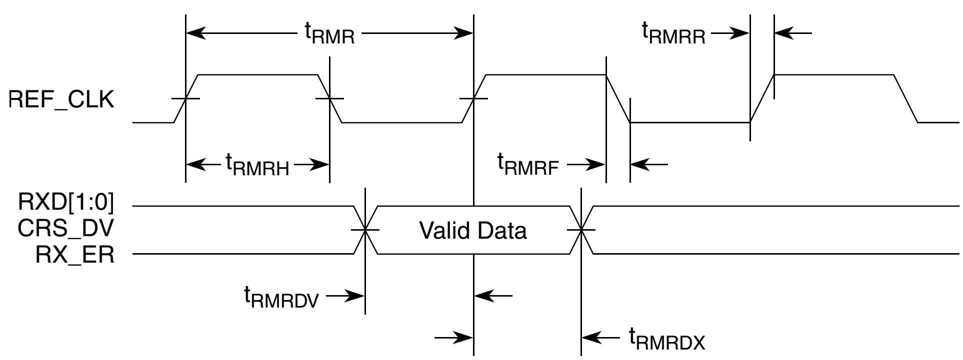


Figure 22. RMII Receive AC Timing Diagram

Figure 37 shows the AC timing diagram for the I^2C bus.

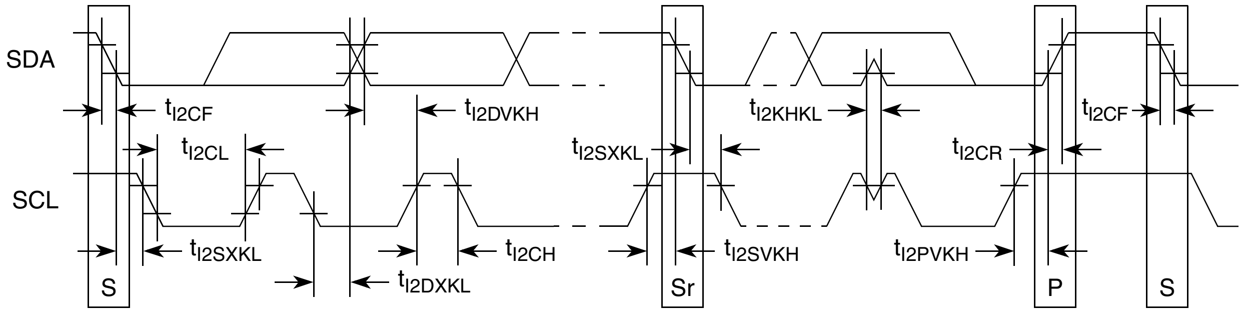


Figure 37. I^2C Bus AC Timing Diagram

13 High-Speed Serial Interfaces (HSSI)

The MPC8641D features two Serializer/Deserializer (SerDes) interfaces to be used for high-speed serial interconnect applications. The SerDes1 interface is dedicated for PCI Express data transfers. The SerDes2 can be used for PCI Express and/or Serial RapidIO data transfers.

This section describes the common portion of SerDes DC electrical specifications, which is the DC requirement for SerDes Reference Clocks. The SerDes data lane's transmitter and receiver reference circuits are also shown.

13.1 Signal Terms Definition

The SerDes utilizes differential signaling to transfer data across the serial link. This section defines terms used in the description and specification of differential signals.

Figure 38 shows how the signals are defined. For illustration purpose, only one SerDes lane is used for description. The figure shows waveform for either a transmitter output (SD*n*_TX and $\overline{\text{SD}n\text{\_TX}}$) or a receiver input (SD*n*_RX and $\overline{\text{SD}n\text{\_RX}}$). Each signal swings between A Volts and B Volts where A > B.

Using this waveform, the definitions are as follows. To simplify illustration, the following definitions assume that the SerDes transmitter and receiver operate in a fully symmetrical differential signaling environment.

1. **Single-Ended Swing**

   The transmitter output signals and the receiver input signals SD*n*_TX, $\overline{\text{SD}n\text{\_TX}}$, SD*n*_RX and $\overline{\text{SD}n\text{\_RX}}$ each have a peak-to-peak swing of A – B Volts. This is also referred as each signal wire's Single-Ended Swing.

2. **Differential Output Voltage, V_{OD}** (or **Differential Output Swing**):

   The Differential Output Voltage (or Swing) of the transmitter, V_{OD}, is defined as the difference of the two complimentary output voltages: $V_{SDn\_TX} - V_{\overline{SDn\_TX}}$. The V_{OD} value can be either positive or negative.

3. **Differential Input Voltage, V_{ID}** (or **Differential Input Swing**):

13.2.3 Interfacing With Other Differential Signaling Levels

With on-chip termination to SGND, the differential reference clocks inputs are HCSL (High-Speed Current Steering Logic) compatible DC-coupled.

Many other low voltage differential type outputs like LVDS (Low Voltage Differential Signaling) can be used but may need to be AC-coupled due to the limited common mode input range allowed (100 to 400 mV) for DC-coupled connection.

LVPECL outputs can produce signal with too large amplitude and may need to be DC-biased at clock driver output first, then followed with series attenuation resistor to reduce the amplitude, in addition to AC-coupling.

NOTE

Figure 43 to Figure 46 below are for conceptual reference only. Due to the fact that clock driver chip's internal structure, output impedance and termination requirements are different between various clock driver chip manufacturers, it is very possible that the clock circuit reference designs provided by clock driver chip vendor are different from what is shown below. They might also vary from one vendor to the other. Therefore, Freescale Semiconductor can neither provide the optimal clock driver reference circuits, nor guarantee the correctness of the following clock driver connection reference circuits. The system designer is recommended to contact the selected clock driver chip vendor for the optimal reference circuits with the MPC8641D SerDes reference clock receiver requirement provided in this document.

Figure 46 shows the SerDes reference clock connection reference circuits for a single-ended clock driver. It assumes the DC levels of the clock driver are compatible with MPC8641D SerDes reference clock input's DC requirement.

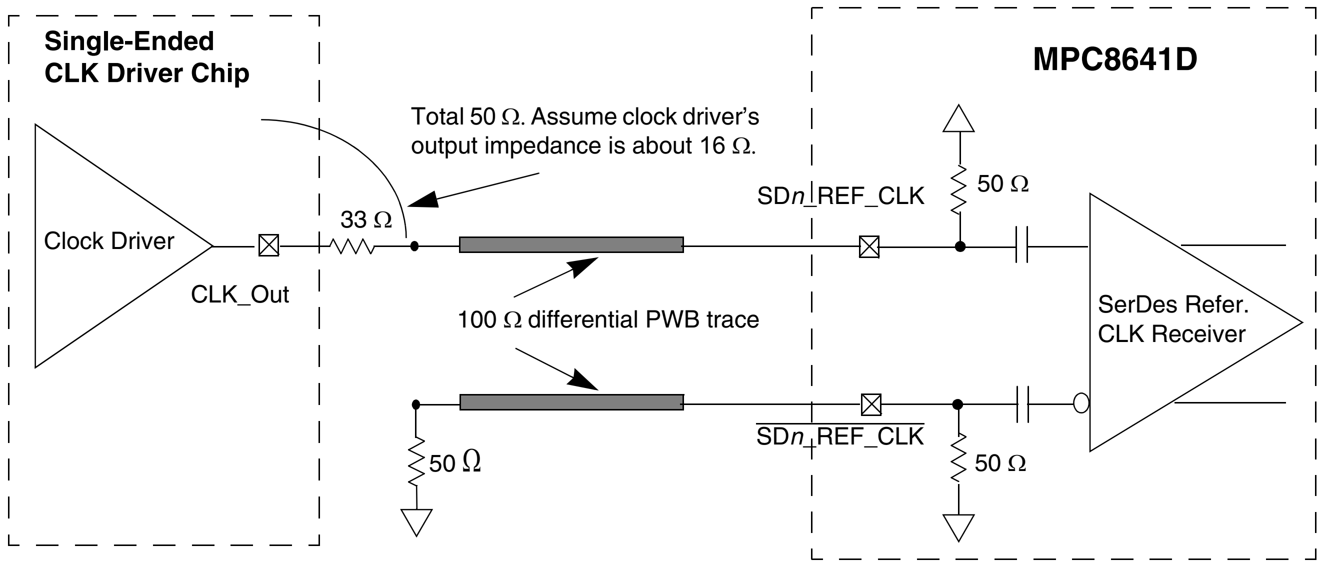


Figure 46. Single-Ended Connection (Reference Only)

Table 54. Short Run Transmitter AC Timing Specifications—3.125 GBaud (continued)

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit Interval	UI	320	320	ps	+/– 100 ppm

Table 55. Long Run Transmitter AC Timing Specifications—1.25 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output Voltage,	V_O	–0.40	2.30	Volts	Voltage relative to COMMON of either signal comprising a differential pair
Differential Output Voltage	V_{DIFFPP}	800	1600	mV p-p	—
Deterministic Jitter	J_D	—	0.17	UI p-p	—
Total Jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit Interval	UI	800	800	ps	+/– 100 ppm

Table 56. Long Run Transmitter AC Timing Specifications—2.5 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output Voltage,	V_O	–0.40	2.30	Volts	Voltage relative to COMMON of either signal comprising a differential pair
Differential Output Voltage	V_{DIFFPP}	800	1600	mV p-p	—
Deterministic Jitter	J_D	—	0.17	UI p-p	—
Total Jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit Interval	UI	400	400	ps	+/– 100 ppm

16 Package

This section details package parameters and dimensions.

16.1 Package Parameters for the MPC8641

The package parameters are as provided in the following list. The package type is 33 mm × 33 mm, 1023 pins. There are two package options: high-lead Flip Chip-Ceramic Ball Grid Array (FC-CBGA), and lead-free (FC-CBGA).

For all package types:

Die size	12.1 mm × 14.7 mm
Package outline	33 mm × 33 mm
Interconnects	1023
Pitch	1 mm
Total Capacitor count	43 caps; 100 nF each

For high-lead FC-CBGA (package option: HCTE[1] HX)

Maximum module height	2.97 mm
Minimum module height	2.47 mm
Solder Balls	89.5% Pb 10.5% Sn
Ball diameter (typical[2])	0.60 mm

For RoHS lead-free FC-CBGA (package option: HCTE[1] VU) and lead-free FC-CBGA (package option: HCTE[1] VJ)

Maximum module height	2.77 mm
Minimum module height	2.27 mm
Solder Balls	95.5% Sn 4.0% Ag 0.5% Cu
Ball diameter (typical[2])	0.60 mm

[1] High-coefficient of thermal expansion

[2] Typical ball diameter is before reflow

8. Note that for MPC8641 (single core) the solder balls for the following signals/pins are not populated in the package: VDD_Core1 (R16, R18, R20, T17, T19, T21, T23, U16, U18, U22, V17, V19, V21, V23, W16, W18, W20, W22, Y17, Y19, Y21, Y23, AA16, AA18, AA20, AA22, AB23, AC24) and SENSEVDD_Core1 (U20).

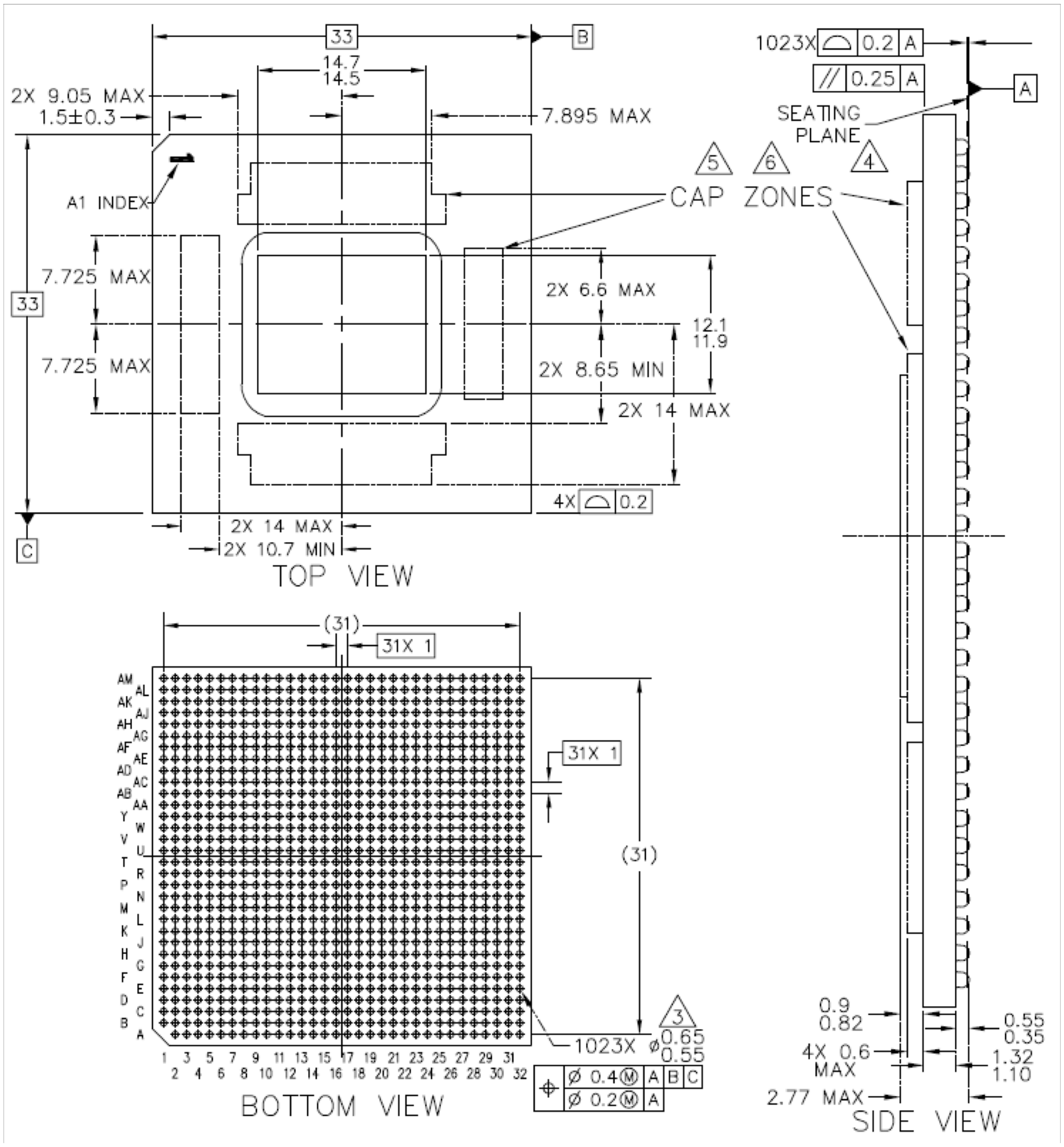


Figure 58. MPC8641D Lead-Free FC-CBGA Dimensions

NOTES for Figure 58

1. All dimensions are in millimeters.
2. Dimensions and tolerances per ASME Y14.5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is defined by the spherical crowns of the solder balls.
5. Capacitors may not be present on all devices.
6. Caution must be taken not to short capacitors or expose metal capacitor pads on package top.
7. All dimensions symmetrical about centerlines unless otherwise specified.
8. Note that for MPC8641 (single core) the solder balls for the following signals/pins are not populated in the package: VDD_Core1 (R16, R18, R20, T17, T19, T21, T23, U16, U18, U22, V17, V19, V21, V23, W16, W18, W20, W22, Y17, Y19, Y21, Y23, AA16, AA18, AA20, AA22, AB23, AC24) and SENSEVDD_Core1 (U20).

Table 63. MPC8641 Signal Reference by Functional Block (continued)

Name[1]	Package Pin Number	Pin Type	Power Supply	Notes
D2_MDQ[0:63]	A7, B7, C5, D5, C8, D8, D6, A5, C4, A3, D3, D2, A4, B4, C2, C1, E3, E1, H4, G1, D1, E4, G3, G2, J4, J2, L1, L3, H3, H1, K1, L4, AA4, AA2, AD1, AD2, Y1, AA1, AC1, AC3, AD5, AE1, AG1, AG2, AC4, AD4, AF3, AF4, AH3, AJ1, AM1, AM3, AH1, AH2, AL2, AL3, AK5, AL5, AK7, AM7, AK4, AM4, AM6, AJ7	I/O	D2_GV$_{DD}$	—
D2_MECC[0:7]	H6, J5, M5, M4, G6, H7, M2, M1	I/O	D2_GV$_{DD}$	—
D2_MDM[0:8]	C7, B3, F4, J1, AB1, AE2, AK1, AM5, K6	O	D2_GV$_{DD}$	—
D2_MDQS[0:8]	B6, B1, F1, K2, AB3, AF1, AL1, AL6, L6	I/O	D2_GV$_{DD}$	—
$\overline{\text{D2\_MDQS}}$[0:8]	A6, A2, F2, K3, AB2, AE3, AK2, AJ6, K5	I/O	D2_GV$_{DD}$	—
D2_MBA[0:2]	W5, V5, P3	O	D2_GV$_{DD}$	—
D2_MA[0:15]	W1, U4, U3, T1, T2, T3, T5, R2, R1, R5, V4, R4, P1, AH5, P4, N1	O	D2_GV$_{DD}$	—
$\overline{\text{D2\_MWE}}$	Y4	O	D2_GV$_{DD}$	—
$\overline{\text{D2\_MRAS}}$	W3	O	D2_GV$_{DD}$	—
$\overline{\text{D2\_MCAS}}$	AB5	O	D2_GV$_{DD}$	—
$\overline{\text{D2\_MCS}}$[0:3]	Y3, AF6, AA5, AF7	O	D2_GV$_{DD}$	—
D2_MCKE[0:3]	N6, N5, N2, N3	O	D2_GV$_{DD}$	23
D2_MCK[0:5]	U1, F5, AJ3, V2, E7, AG4	O	D2_GV$_{DD}$	—
$\overline{\text{D2\_MCK}}$[0:5]	V1, G5, AJ4, W2, E6, AG5	O	D2_GV$_{DD}$	—
D2_MODT[0:3]	AE6, AG7, AE5, AH6	O	D2_GV$_{DD}$	—
D2_MDIC[0:1]	F8, F7	IO	D2_GV$_{DD}$	27
D2_MV$_{REF}$	A18	DDR Port 2 reference voltage	D2_GV$_{DD}$ /2	3
High Speed I/O Interface 1 (SERDES 1)[4]				
SD1_TX[0:7]	L26, M24, N26, P24, R26, T24, U26, V24	O	SV$_{DD}$	—
$\overline{\text{SD1\_TX}}$[0:7]	L27, M25, N27, P25, R27, T25, U27, V25	O	SV$_{DD}$	—
SD1_RX[0:7]	J32, K30, L32, M30, T30, U32, V30, W32	I	SV$_{DD}$	—
$\overline{\text{SD1\_RX}}$[0:7]	J31, K29, L31, M29, T29, U31, V29, W31	I	SV$_{DD}$	—
SD1_REF_CLK	N32	I	SV$_{DD}$	—
$\overline{\text{SD1\_REF\_CLK}}$	N31	I	SV$_{DD}$	—
SD1_IMP_CAL_TX	Y26	Analog	SV$_{DD}$	19
SD1_IMP_CAL_RX	J28	Analog	SV$_{DD}$	30
SD1_PLL_TPD	U28	O	SV$_{DD}$	13, 17

Table 63. MPC8641 Signal Reference by Functional Block (continued)

Name[1]	Package Pin Number	Pin Type	Power Supply	Notes
TSEC3_TX_EN	AH19	O	TV_{DD}	36
TSEC3_TX_ER	AH17	O	TV_{DD}	—
TSEC3_TX_CLK	AH18	I	TV_{DD}	40
TSEC3_GTX_CLK	AG19	O	TV_{DD}	41
TSEC3_CRS	AE15	I/O	TV_{DD}	37
TSEC3_COL	AF15	I	TV_{DD}	—
TSEC3_RXD[0:7]	AJ17, AE16, AH16, AH14, AJ19, AH15, AG16, AE19	I	TV_{DD}	—
TSEC3_RX_DV	AG15	I	TV_{DD}	—
TSEC3_RX_ER	AF16	I	TV_{DD}	—
TSEC3_RX_CLK	AJ18	I	TV_{DD}	40
eTSEC Port 4 Signals[5]				
TSEC4_TXD[0:3]	AC18, AC16, AD18, AD17	O	TV_{DD}	6
TSEC4_TXD[4]	AD16	O	TV_{DD}	25
TSEC4_TXD[5:7]	AB18, AB17, AB16	O	TV_{DD}	6
TSEC4_TX_EN	AF17	O	TV_{DD}	36
TSEC4_TX_ER	AF19	O	TV_{DD}	—
TSEC4_TX_CLK	AF18	I	TV_{DD}	40
TSEC4_GTX_CLK	AG17	O	TV_{DD}	41
TSEC4_CRS	AB14	I/O	TV_{DD}	37
TSEC4_COL	AC13	I	TV_{DD}	—
TSEC4_RXD[0:7]	AG14, AD13, AF13, AD14, AE14, AB15, AC14, AE17	I	TV_{DD}	—
TSEC4_RX_DV	AC15	I	TV_{DD}	—
TSEC4_RX_ER	AF14	I	TV_{DD}	—
TSEC4_RX_CLK	AG13	I	TV_{DD}	40
Local Bus Signals[5]				
LAD[0:31]	A30, E29, C29, D28, D29, H25, B29, A29, C28, L22, M22, A28, C27, H26, G26, B27, B26, A27, E27, G25, D26, E26, G24, F27, A26, A25, C25, H23, K22, D25, F25, H22	I/O	OV_{DD}	6
LDP[0:3]	A24, E24, C24, B24	I/O	OV_{DD}	6, 22
LA[27:31]	J21, K21, G22, F24, G21	O	OV_{DD}	6, 22
$\overline{\text{LCS}}$[0:4]	A22, C22, D23, E22, A23	O	OV_{DD}	7
$\overline{\text{LCS}}$[5]/$\overline{\text{DMA\_DREQ}}$[2]	B23	O	OV_{DD}	7, 9, 10

Table 63. MPC8641 Signal Reference by Functional Block (continued)

Name[1]	Package Pin Number	Pin Type	Power Supply	Notes
TSEC3_TXD[6:7]/ cfg_tsec3_prtcl[0:1]	AL20, AL19	—	LV_{DD}	—
TSEC4_TXD[0:3]/ cfg_io_ports[0:3]	AC18, AC16, AD18, AD17	—	LV_{DD}	—
TSEC4_TXD[5]/ cfg_tsec4_reduce	AB18	—	LV_{DD}	—
TSEC4_TXD[6:7]/ cfg_tsec4_prtcl[0:1]	AB17, AB16	—	LV_{DD}	—
LAD[0:31]/ cfg_gpporcr[0:31]	A30, E29, C29, D28, D29, H25, B29, A29, C28, L22, M22, A28, C27, H26, G26, B27, B26, A27, E27, G25, D26, E26, G24, F27, A26, A25, C25, H23, K22, D25, F25, H22	—	OV_{DD}	—
$\overline{\text{LWE[0]}}$/ cfg_cpu_boot	E21	—	OV_{DD}	—
$\overline{\text{LWE[1]}}$/ cfg_rio_sys_size	F21	—	OV_{DD}	—
$\overline{\text{LWE[2:3]}}$/ cfg_host_agt[0:1]	D22, E20	—	OV_{DD}	—
LDP[0:3], LA[27] / cfg_core_pll[0:4]	A24, E24, C24, B24, J21	—	OV_{DD}	22
LA[28:31]/ cfg_sys_pll[0:3]	K21, G22, F24, G21	—	OV_{DD}	22
LGPL[3], LGPL[5]/ cfg_boot_seq[0:1]	K20, J19	—	OV_{DD}	—
D1_MSRCID[0]/ cfg_mem_debug	F15	—	OV_{DD}	—
D1_MSRCID[1]/ cfg_ddr_debug	K15	—	OV_{DD}	—

Table 63. MPC8641 Signal Reference by Functional Block (continued)

Name[1]	Package Pin Number	Pin Type	Power Supply	Notes

37.This pin is only an output in FIFO mode when used as Rx Flow Control.

38.This pin functions as cfg_dram_type[0 or 1] at reset and MUST BE VALID BEFORE HRESET ASSERTION in device sleep mode.

39. Should be pulled to ground if unused (such as in FIFO, MII and RMII modes).

40. See Section 18.4.2, "Platform to FIFO Restrictions" for clock speed limitations for this pin when used in FIFO mode.

41. The phase between the output clocks TSEC1_GTX_CLK and TSEC2_GTX_CLK (ports 1 and 2) is no more than 100 ps. The phase between the output clocks TSEC3_GTX_CLK and TSEC4_GTX_CLK (ports 3 and 4) is no more than 100 ps.

42. For systems which boot from Local Bus (GPCM)-controlled flash, a pullup on LGPL4 is required.

Special Notes for Single Core Device:

S1. Solder ball for this signal will not be populated in the single core package.

S2. The PLL filter from V_{DD}_Core1 to AV_{DD}_Core1 should be removed. AV_{DD}_Core1 should be pulled to ground with a weak (2–10 kΩ) resistor. See Section 20.2.1, "PLL Power Supply Filtering" for more details.

S3. This pin should be pulled to GND for the single core device.

S4. No special requirement for this pin on single core device. Pin should be tied to power supply as directed for dual core.

18 Clocking

This section describes the PLL configuration of the MPC8641. Note that the platform clock is identical to the MPX clock.

18.1 Clock Ranges

Table 64 provides the clocking specifications for the processor cores and Table 65 provides the clocking specifications for the memory bus. Table 66 provides the clocking for the Platform/MPX bus and Table 67 provides the clocking for the Local bus.

Table 64. Processor Core Clocking Specifications

Characteristic	Maximum Processor Core Frequency								Unit	Notes
	1000 MHz		1250MHz		1333MHz		1500 MHz			
	Min	Max	Min	Max	Min	Max	Min	Max		
e600 core processor frequency	800	1000	800	1250	800	1333	800	1500	MHz	1, 2

Notes:

1. **Caution:** The MPX clock to SYSCLK ratio and e600 core to MPX clock ratio settings must be chosen such that the resulting SYSCLK frequency, e600 (core) frequency, and MPX clock frequency do not exceed their respective maximum or minimum operating frequencies. Refer to Section 18.2, "MPX to SYSCLK PLL Ratio," and Section 18.3, "e600 to MPX clock PLL Ratio," for ratio settings.
2. The minimum e600 core frequency is based on the minimum platform clock frequency of 400 MHz.

20 System Design Information

This section provides electrical and thermal design recommendations for successful application of the MPC8641.

20.1 System Clocking

This device includes six PLLs, as follows:

1. The platform PLL generates the platform clock from the externally supplied SYSCLK input. The frequency ratio between the platform and SYSCLK is selected using the platform PLL ratio configuration bits as described in Section 18.2, "MPX to SYSCLK PLL Ratio."
2. The dual e600 Core PLLs generate the e600 clock from the externally supplied input.
3. The local bus PLL generates the clock for the local bus.
4. There are two internal PLLs for the SerDes block.

20.2 Power Supply Design and Sequencing

20.2.1 PLL Power Supply Filtering

Each of the PLLs listed above is provided with power through independent power supply pins.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide independent filter circuits per PLL power supply as illustrated in Figure 64, one to each of the AV_{DD} type pins. By providing independent filters to each PLL the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLLs resonant frequency range from a 500 kHz to 10 MHz range. It should be built with surface mount capacitors with minimum Effective Series Inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit should be placed as close as possible to the specific AV_{DD} type pin being supplied to minimize noise coupled from nearby circuits. It should be possible to route directly from the capacitors to the AV_{DD} type pin, which is on the periphery of the footprint, without the inductance of vias.

Figure 63 and Figure 64 show the PLL power supply filter circuits for the platform and cores, respectively.

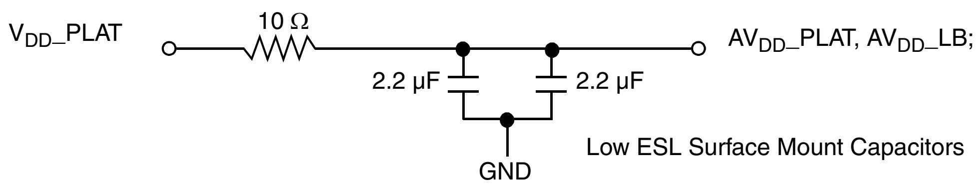


Figure 63. MPC8641 PLL Power Supply Filter Circuit (for platform and Local Bus)